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## **FDMC8327L**

## N-Channel PowerTrench<sup>®</sup> MOSFET **40 V, 14 A, 9.7 m**Ω

#### **Features**

- Max r<sub>DS(on)</sub> = 9.7 mΩ at V<sub>GS</sub> = 10 V, I<sub>D</sub> = 12 A
- Max  $r_{DS(on)}$  = 12.5 m $\Omega$  at V<sub>GS</sub> = 4.5 V, I<sub>D</sub> = 10 A
- Low Profile 0.8mm max in Power 33
- 100% UIL test
- RoHS Compliant

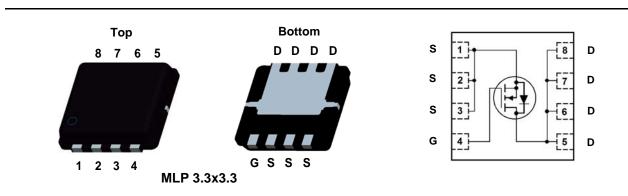


## **General Description**

This N-Channel MOSFET is produced using Fairchild Semiconductor's advanced Power Trench® process that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance.

## Application

DC-DC Conversion



#### MOSFET Maximum Ratings T<sub>A</sub> = 25 °C unless otherwise noted

Symbol	Parameter			Ratings	Units	
V <sub>DS</sub>	Drain to Source Voltage			40	V	
V <sub>GS</sub>	Gate to Source Voltage			±20	V	
ID	Drain Current - Continuous (Package limited) T <sub>C</sub> = 25 °C			14		
	- Continuous (Silicon limited) T <sub>C</sub> = 25 °C			43		
	- Continuous	T <sub>A</sub> = 25 °C	(Note 1a)	12	A	
	- Pulsed			60		
E <sub>AS</sub>	Single Pulse Avalanche Energy		(Note 3)	25	mJ	
P <sub>D</sub>	Power Dissipation	T <sub>C</sub> = 25 °C		30	W	
	Power Dissipation	T <sub>A</sub> = 25 °C	(Note 1a)	2.3	VV	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range		-55 to +150	°C		
Thermal Ch	naracteristics					
$R_{\theta JC}$	Thermal Resistance, Junction to Case (Note 1)		4.2	°C/W		
-			(A. A. A	50	- C/VV	

#### Thermal Resistance, Junction to Ambient (Note 1a) $R_{\theta JA}$

#### **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMC8327L	FDMC8327L	Power 33	13 "	12 mm	3000 units

October 2013

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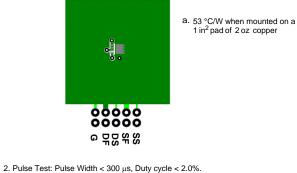
53

Symbol	Parameter	Test Condi	tions	Min	Тур	Max	Units
Off Chara	cteristics						
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	I <sub>D</sub> = 250 μA, V <sub>GS</sub> = 0 V		40			V
ΔBV <sub>DSS</sub> ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	$I_D = 250 \ \mu A$ , referenced to	o 25 °C		22		mV/°C
IDSS	Zero Gate Voltage Drain Current	$V_{DS} = 32 \text{ V}, V_{GS} = 0 \text{ V}$				1	μΑ
I <sub>GSS</sub>	Gate to Source Leakage Current	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$				±100	nA
On Chara	cteristics						
V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \ \mu A$		1.0	1.7	3.0	V
$\Delta V_{GS(th)} \Delta T_J$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = 250 \ \mu A$ , referenced to	o 25 ℃		-5		mV/°C
r <sub>DS(on)</sub>		V <sub>GS</sub> = 10 V, I <sub>D</sub> = 12 A			7.4	9.7	mΩ
	Static Drain to Source On Resistance	$V_{GS} = 4.5 \text{ V}, \ I_D = 10 \text{ A}$			9.4	12.5	
		$V_{GS} = 10 \text{ V}, \ I_D = 12 \text{ A}, \text{ T}_J$	T <sub>J</sub> = 125 °C 11 1		14.5	5	
9fs	Forward Transconductance	$V_{DD} = 5 V, I_D = 12 A$			52		S
Dynamic C <sub>iss</sub>	Characteristics				1235	1850	pF
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> = 20 V, V <sub>GS</sub> = 0 V, f = 1 MHZ			347	520	pF
C <sub>rss</sub>	Reverse Transfer Capacitance				21	35	pF
R <sub>g</sub>	Gate Resistance			0.1	0.6	1.3	Ω
	Characteristics	1			1	I	
t <sub>d(on)</sub>	Turn-On Delay Time	$V_{DD}$ = 20 V, I <sub>D</sub> = 12 A, V <sub>GS</sub> = 10 V, R <sub>GEN</sub> = 6 $\Omega$			8.4	17	ns
t <sub>r</sub>	Rise Time				2.2	10	ns
t <sub>d(off)</sub>	Turn-Off Delay Time				20	32	ns
t <sub>f</sub>	Fall Time	-			2.2	10	ns
Q <sub>g(TOT)</sub>	Total Gate Charge	$V_{GS} = 0V$ to 10 V	( 00.)(		18.5	26	nC
Q <sub>g(TOT)</sub>	Total Gate Charge	$V_{GS} = 0V \text{ to } 5 \text{ V}$ $I_D = 12 \text{ A}$			9.7	14	nC
Q <sub>gs</sub>	Gate to Source Charge				3.3		nC
Q <sub>gd</sub>	Gate to Drain "Miller" Charge				2.6		nC
Drain-Soເ	urce Diode Characteristics						
	Source to Drain Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 1.8 A	(Note 2)		0.7	1.2	
V <sub>SD</sub>		$V_{GS} = 0 V, I_S = 12 A$	(Note 2)		0.8	1.3	- V
t <sub>rr</sub>	Reverse Recovery Time	I <sub>F</sub> = 12 A, di/dt = 100 A/s			32	51	ns
		$I_F = 12 \text{ A}, \text{ ui/ut} = 100 \text{ A/S}$					

Notes:

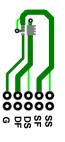
 $Q_{rr}$ 

1. R<sub>0JA</sub> is determined with the device mounted on a 1 in<sup>2</sup> pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R<sub>0JC</sub> is guaranteed by design while R<sub>0CA</sub> is determined by the user's board design.



3. Starting T\_J = 25 °C; N-ch: L = 0.3 mH, I\_{AS} = 13 A, V\_DD = 36 V, V\_{GS} = 10 V.

Reverse Recovery Charge



b. 125 °C/W when mounted on a minimum pad of 2 oz copper

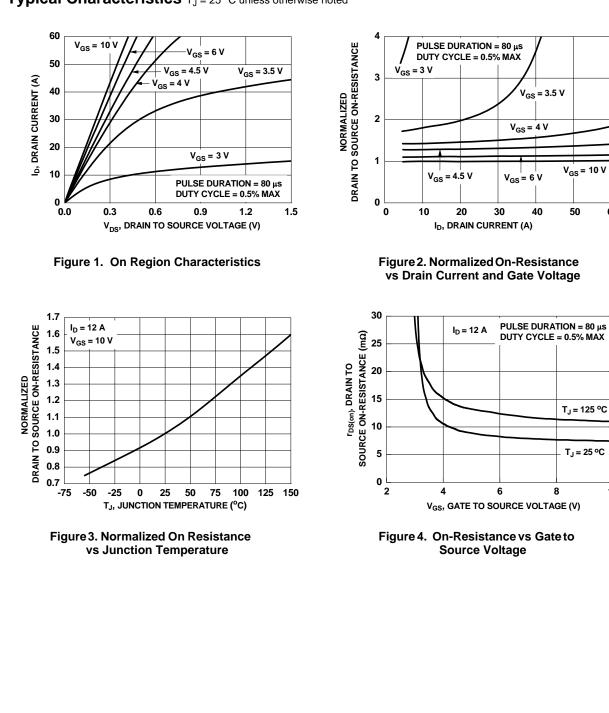
10

20

nC

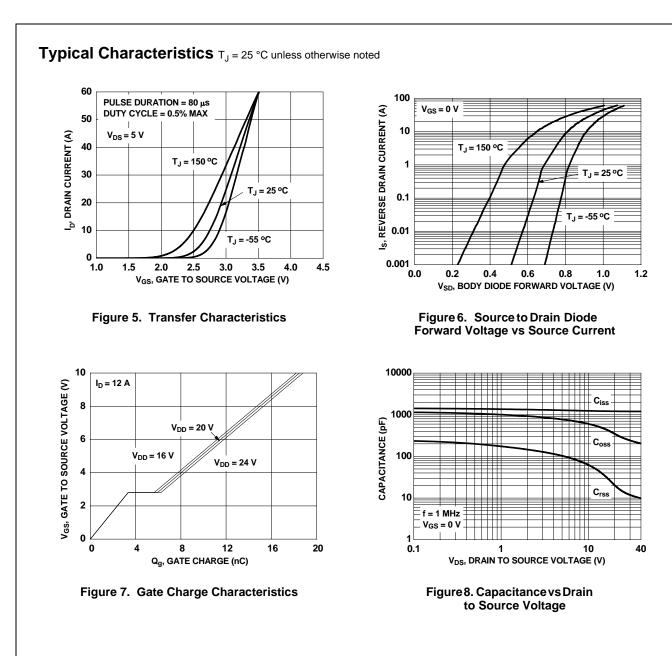
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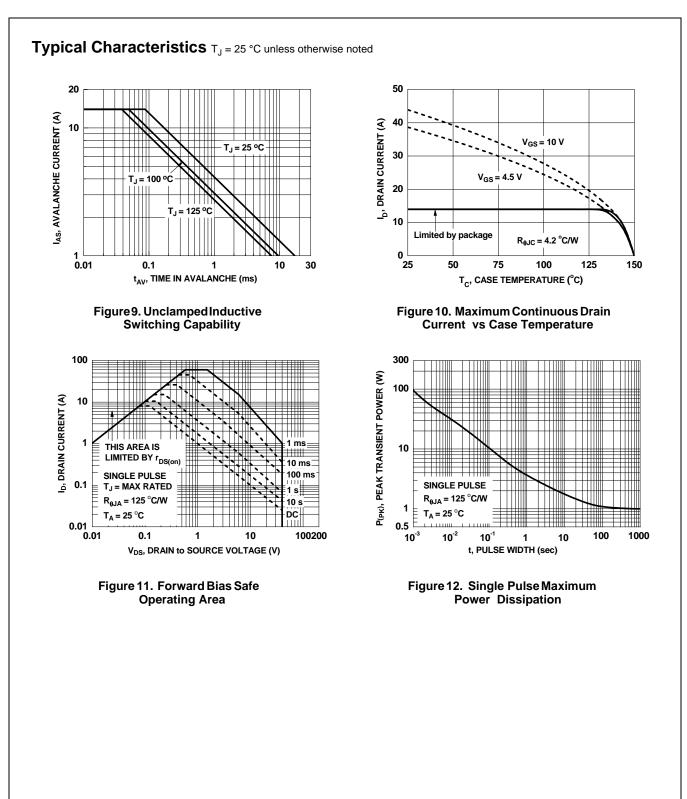
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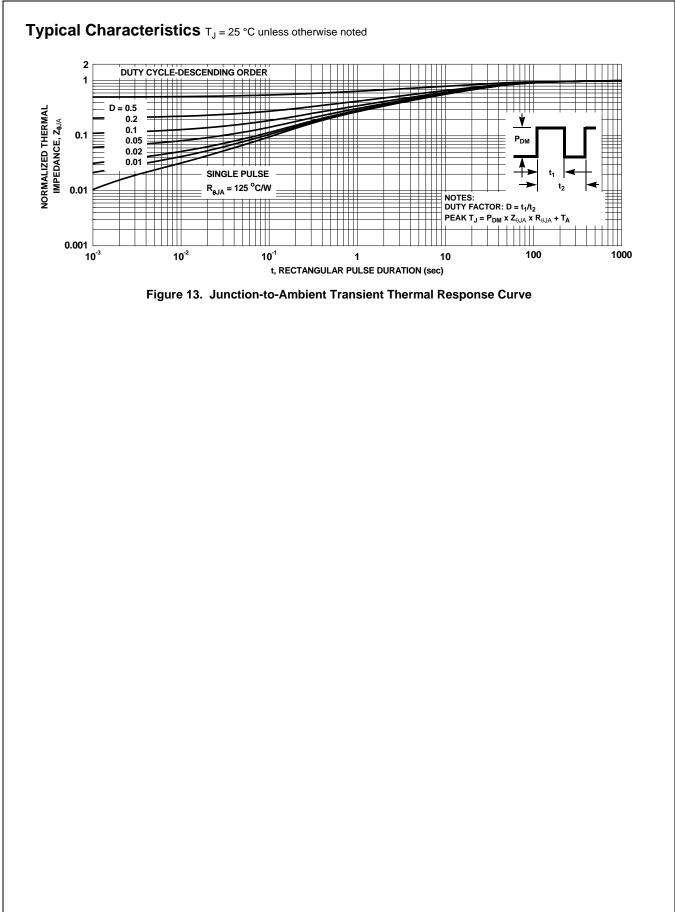
## Typical Characteristics T<sub>J</sub> = 25 °C unless otherwise noted

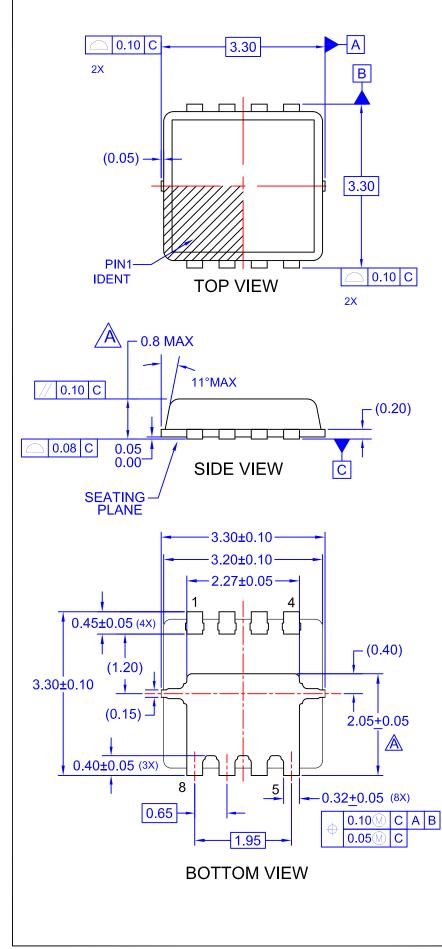


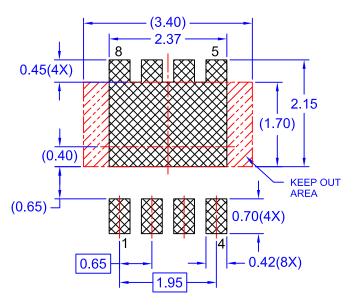




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## RECOMMENDED LAND PATTERN

**NOTES:** 

- A EXCEPT AS NOTED, PACKAGE CONFORMS TO JEDEC REGISTRATION MO-240 VARIATION BA.
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 2009.
- D. SEATING PLANE IS DEFINED BY TERMINAL TIPS ONLY
- E. BODY DIMENSIONS DO NOT INCLUDE MOLD FLASH PROTRUSIONS NOR GATE BURRS.
- F. FLANGE DIMENSIONS INCLUDE INTERTERMINAL FLASH OR PROTRUSION. INTERTERMINAL FLASH OR PROTRUSION SHALL NOT EXCEED 0.25MM PER SIDE.
- G. IT IS RECOMMENDED TO HAVE NO TRACES OR VIA WITHIN THE KEEP OUT AREA.
- H. DRAWING FILENAME: MKT-MLP08Trev4.
- I. GENERAL RADII FOR ALL CORNERS SHALL BE 0.20MM MAX.





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No Identification Needed	Full Production	Datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve the design.			
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